

Supplementary Information for Low-Temperature Fabrication of Lithium Aluminum Oxide Phosphate Solid Electrolyte Thin Films from Aqueous Precursors

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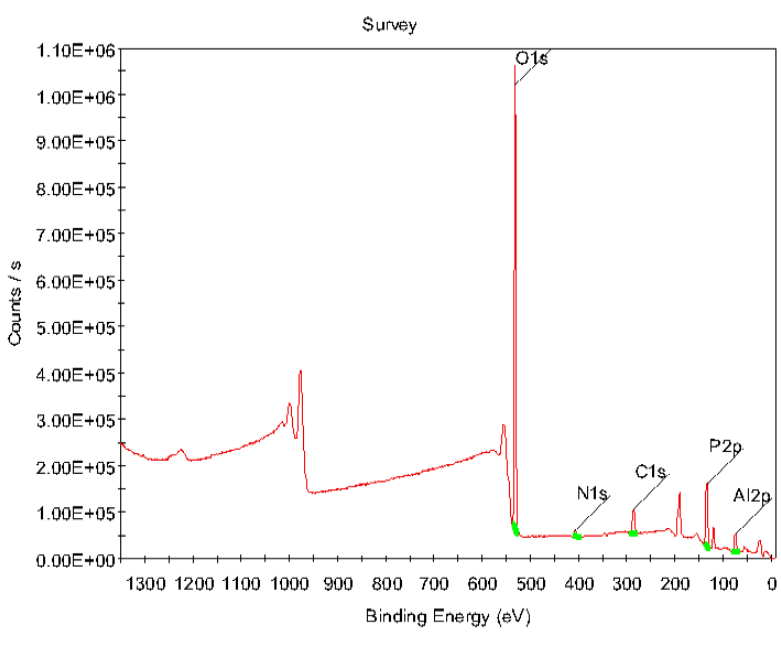


Figure S1. XPS survey scan of LiAlPO films annealed at 275 °C.

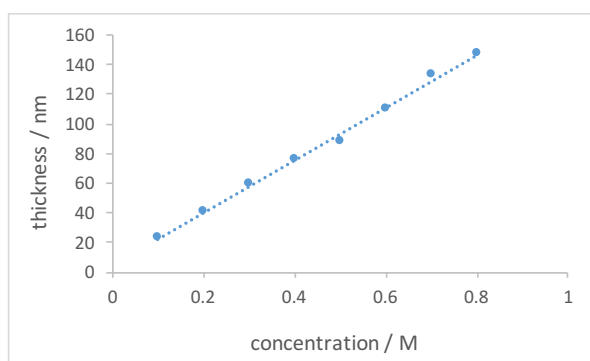


Figure S2. Thickness as a function of precursor concentration for LiAlPO films resulting from spin-coating precursor solutions at 3000 rpm for 30 s followed by annealing at 275 °C, as determined by x-ray reflectivity and confirmed via ellipsometry.

Table S1. Atomic ratios of LiAlPO films annealed at 275 °C by XPS

Peak	Atomic Ratio
Al 2p	1
Li 1s	2.5
N 1s	0.1
P 2p	1.6
O 1s	5.8